Application/Control No. Applicant(s)/Patent Under Reexamination 10/707,361 CHEN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Mathieu D. Vargot 1732 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-6,146,577 11-2000 Yamaki et al. 264/500 Α US-6,625,379 09-2003 Azuma, Naoki 385/146 В С US-US-D US-E US-F US-G USн US-US-J US-Κ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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